

1. (*Unamended*) An insulator capacitance analyzer for analyzing C-V characteristics of a first MIS structure having unknown capacitance, comprising:
a capacitance structure having known capacitance and configured so as to be serially connectable to the first MIS structure; and
a measuring section for measuring synthesis capacitance of the serially-connected first MIS structure and capacitance structure.

8. (*Unamended*) An insulator capacitance analyzer for analyzing C-V characteristics of a first MIS (Metal/Insulator/Semiconductor) structure, comprising:
a capacitance structure having a known capacitance and serially connected to the first MIS structure; and
a measuring section for measuring a synthesis capacitance of the serially-connected first MIS structure and the capacitance structure.

REMARKS

This is in response to the Office Action dated April 8, 2003. Claims 1-10 are pending.

Applicant notes with appreciation the Examiner's indication that claims 4 and 10 contain allowable subject matter.

Claim 1

Claim 1 stands rejected under 35 U.S.C. Section 102(b) as being allegedly anticipated by JP 06-112289. This Section 102(b) rejection is respectfully traversed for at least the following reasons.